

I claim:

1. A calibration method for a test system wherein semiconductor components are tested by making contact with a component to be tested via a probe card, the method which comprises:

providing a test substrate having mutually separated connecting contact points for a probe of a probe card, having mutually separated further connecting contact points for a reference probe, and having conductor tracks each connecting one of the connecting contact points to a respective one of the further connecting contact points to define contact point pairs;

placing a probe of a probe card on a connecting contact point and placing a reference probe onto the further connecting contact point of a respective contact point pair; and

calibrating the test system, including the probe card, by using the reference probe as a reference point for a respective signal path.

2. The method according to claim 1, which comprises placing the test substrate into a holder and indexing the test substrate onward, to connect the probes belonging to a probe

card successively to various connecting contact points on the test substrate.

3. The method according to claim 2, wherein the indexing step comprises moving the holder together with the test substrate.

4. The method according to claim 2, wherein the indexing step comprises moving the test substrate in the holder onward.

5. The method according to claim 1, wherein the providing step comprises providing a test substrate having conductor tracks between connecting contact point and the further connecting contact point of a contact point pair of approximately the same length.

6. The method according to claim 1, wherein the providing step comprises providing a test substrate having the further connecting contact points arranged in a straight line.

7. A test substrate for calibrating a test system for semiconductor components, comprising a plurality of connecting contact points connected in pairs, said contact points of said pairs being disposed at mutually different distances from one another, and a plurality of conductor tracks of substantially equal length respectively connecting said pairs of contact points.